

<b>Notice of References Cited</b>	Application/Control No. 10/650,591	Applicant(s)/Patent Under Reexamination AFEYAN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	L	US-			
	M	US-			

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*	U	Holvoet et al. JBC 1991, vol. 266, pp 19717-10724
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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